

Multiplicative Error Models for Count Time Series



HELMUT SCHMIDT
UNIVERSITÄT
Universität der Bundeswehr Hamburg

MATH
STAT

Christian H. Weiß

Department of Mathematics & Statistics,
Helmut Schmidt University, Hamburg

Fukang Zhu

School of Mathematics, Jilin University,
Changchun, China



HELMUT SCHMIDT
UNIVERSITÄT
Universität der Bundeswehr Hamburg

MATH
STAT

Multiplicative Error Models for Count Time Series

Introduction

Multiplicative error models (MEMs), see Engle (2002),
Brownlees et al. (2012), Cipollini & Gallo (2023)
for positively real-valued process $(Y_t)_{t \in \mathbb{Z} = \{\dots, -1, 0, 1, \dots\}}$:

$$Y_t = \mu_t \cdot \varepsilon_t,$$

where $\mu_t | \mathcal{F}_{t-1}$ deterministic, truly positive number,
 ε_t positively real-valued RV with $E[\varepsilon_t | \mathcal{F}_{t-1}] = E[\varepsilon_t] = 1$
and $\sigma_t^2 := V[\varepsilon_t | \mathcal{F}_{t-1}] = V[\varepsilon_t] \in (0, \infty)$.

Observations (Y_t) satisfy

$$E[Y_t | \mathcal{F}_{t-1}] = \mu_t, \quad V[Y_t | \mathcal{F}_{t-1}] = \sigma_t^2 \mu_t^2.$$

Special case, see Engle & Russell (1998):

If (ε_t) i. i. d. with mean 1 and variance σ^2 ,

and if linear recursive scheme

$$\mu_t = a_0 + \underbrace{\sum_{i=1}^p a_i Y_{t-i}}_{\text{autoregression}} + \underbrace{\sum_{j=1}^q b_j \mu_{t-j}}_{\text{feedback}}$$

with $a_0 > 0$, $a_1, \dots, b_q \geq 0$, and $\sum_{i=1}^p a_i + \sum_{j=1}^q b_j < 1$,

then **autoregressive conditional duration** (ACD) model.

Here: not positively real-valued process (Y_t) ,
but (positively integer-valued) count process (X_t) .

Integer counterpart: **INGARCH models** by Heinen (2003), Ferland et al. (2006) for count process (X_t) with range $\mathbb{N}_0 = \{0, 1, \dots\}$. With $M_t = E[X_t | \mathcal{F}_{t-1}]$, model equation

$$M_t = a_0 + \sum_{i=1}^p a_i X_{t-i} + \sum_{j=1}^q b_j M_{t-j},$$

$X_t | \mathcal{F}_{t-1}$ from conditional count distribution with mean M_t .

Default model: $X_t | \mathcal{F}_{t-1} \sim \text{Poi}(M_t)$,

but many further conditional distributions, see Weiß (2018).

Crucial difference to ACD-MEM:

no explicit multiplicative structure.

Absence of multiplicative structure because of
“multiplication problem”, see Weiß (2018):
multiplication $M \cdot \epsilon$ of count RV ϵ by real scalar $M \in (0, \infty)$
does not lead to count value anymore.

In context of **INARMA models**, so-called
“thinning operators” as integer substitutes of multiplication:
random operator “thinn” from \mathbb{N}_0 to \mathbb{N}_0 ,
where $E[\text{thinn}(\epsilon) \mid \epsilon] \leq \epsilon$.

Family of **generalized thinnings** by Latour (1998):

$$\alpha \bullet_\nu \epsilon := \sum_{j=1}^{\epsilon} Z_j \quad \text{with } E[Z_j] = \alpha \in (0, 1) \text{ and } V[Z_j] = \nu > 0,$$

where Z_j i. i. d. count RV (**counting series**).

Thus, $E[\alpha \bullet_\nu \epsilon \mid \epsilon] = \alpha \cdot \epsilon \leq \epsilon$,

so integer substitute of multiplication in a sense.

Popular examples:

- binomial thinning $\alpha \circ \epsilon \mid \epsilon \sim \text{Bin}(\epsilon, \alpha)$;
 - negative-binomial thinning $\alpha * \epsilon \mid \epsilon \sim \text{NB}(\epsilon, 1/(1 + \alpha))$;
 - Poisson thinning $\alpha \bullet_\nu \epsilon \mid \epsilon \sim \text{Poi}(\epsilon \cdot \alpha)$.
-

Outline:

- multiplicative operators for counts;
- used to define count MEM (CMEM);
- two specific cases using compounding operator and binomial multiplicative operator, respectively;
- semi-parametric estimation methods;
- illustrative real-world data examples.



Multiplicative Operators for Counts

Definition & Properties

“ $\alpha \odot : \mathbb{N}_0 \rightarrow \mathbb{N}_0$ ” integer-valued **multiplicative operator** if

$$E[\alpha \odot \epsilon \mid \epsilon] = \alpha \cdot \epsilon \quad \text{for all } \alpha > 0,$$

so multiplicative in conditional mean of $\alpha \odot \epsilon$.

It follows that $E[\alpha \odot \epsilon] = \alpha \cdot E[\epsilon]$.

Further assumptions for (conditional) variance of $\alpha \odot \epsilon$, e. g.,

$$\text{if } V[\alpha \odot \epsilon \mid \epsilon] = \nu \cdot \epsilon, \quad \text{then} \quad V[\alpha \odot \epsilon] = \nu E[\epsilon] + \alpha^2 V[\epsilon]$$

for some $\nu = \nu(\alpha) > 0$. For likelihood calculation or simulation, necessary to fully specify conditional distribution of $\alpha \odot \epsilon \mid \epsilon$.

Special case: **compounding operator**

$$\alpha \bullet_\nu \epsilon := \sum_{j=1}^{\epsilon} Z_j \quad \text{with i. i. d. counting series } (Z_j),$$

having mean $\alpha > 0$ and variance $\nu > 0$,

where distribution of $\alpha \bullet_\nu \epsilon$ is convolution

$$P(\alpha \bullet_\nu \epsilon = k) = \sum_{l=0}^{\infty} P(\epsilon = l) \cdot P(\alpha \bullet_\nu l = k).$$

Important examples: Poisson or geometric counting series,

$$\alpha \bullet_\nu l \sim \begin{cases} \text{Poi}(l\alpha) & \text{if } Z_j \sim \text{Poi}(\alpha), \\ \text{NB}\left(l, 1/(1+\alpha)\right) & \text{if } Z_j \sim \text{NB}\left(1, 1/(1+\alpha)\right). \end{cases}$$

Bernoulli counting series $Z_j \sim \text{Bin}(1, \alpha)$ not suitable,
 because then $\alpha < 1$ and $\alpha \bullet_\nu l \leq l!$

Special case: **binomial multiplicative operator**

$$\alpha \otimes \epsilon = \lfloor \alpha \rfloor \cdot \epsilon + \text{Bin}(\epsilon, \alpha - \lfloor \alpha \rfloor) \quad \text{for any } \alpha > 0,$$

where $E[\alpha \otimes \epsilon \mid \epsilon] = \alpha \cdot \epsilon$ and

$$V[\alpha \otimes \epsilon \mid \epsilon] = (\alpha - \lfloor \alpha \rfloor)(1 - \alpha + \lfloor \alpha \rfloor)\epsilon =: \nu(\alpha) \cdot \epsilon.$$

Distribution determined by

$$\text{pgf}_{\alpha \otimes \epsilon}(u) = \text{pgf}_\epsilon \left(u^{\lfloor \alpha \rfloor} (1 - (\alpha - \lfloor \alpha \rfloor) + (\alpha - \lfloor \alpha \rfloor)u) \right).$$



MEMs for Count Time Series

Definition & Properties

(X_t) with range \mathbb{N}_0 is **CMEM** if $X_t = M_t \odot \epsilon_t$,

where $M_t | \mathcal{F}_{t-1}$ deterministic truly positive number.

(ϵ_t) i. i. d. count RV with $E[\epsilon_t] = 1$ and $V[\epsilon_t] = \sigma^2$.

Operator “ \odot ” executed independently of \mathcal{F}_{t-1} and ϵ_t .

We have $E[X_t | \mathcal{F}_{t-1}] = M_t$. **INGARCH**(p, q)-**CMEM** if

$$M_t = f(X_{t-1}, \dots, X_{t-p}, M_{t-1}, \dots, M_{t-q}), \quad p \geq 1, q \geq 0.$$

If “ \odot ” also satisfies $V[\alpha \odot \epsilon | \epsilon] = \nu(\alpha) \cdot \epsilon$, then

$$V[X_t | \mathcal{F}_{t-1}] = \nu(M_t) + \sigma^2 M_t^2.$$

Establish existence using Doukhan & Neumann (2019).

Special case: **compounding CMEM** $X_t = M_t \bullet_\nu \epsilon_t$,
satisfying

$$E[X_t | \mathcal{F}_{t-1}] = M_t, \quad V[X_t | \mathcal{F}_{t-1}] = \nu(M_t) + \sigma^2 M_t^2.$$

Poi-counting series: $\nu(M_t) = M_t$; NB-c.s.: $\nu(M_t) = M_t(1 + M_t)$.

In Weiß & Zhu (2023), we prove:

- first-order stationary iff $\sum_{i=1}^p a_i + \sum_{j=1}^q b_j < 1$;
- conditions for second-order stationarity;
- moment formulae, YW-type equations for ACF;
- CP-INGARCH process stationary and ergodic.

Possible competitor by Aknouche & Scotto (2023):
 multiplicative thinning-based INGARCH model ($m \in \mathbb{N}$ specified)

$$X_t = \lambda_t \cdot \epsilon_t, \quad \lambda_t = 1 + \omega \circ m + \sum_{i=1}^q \alpha_i \circ Y_{t-i} + \sum_{j=1}^p \beta_j \circ \lambda_{t-j}.$$

Relation of our INGARCH-CMEM to ordinary INGARCH:

- $X_t = M_t \bullet_\nu \epsilon_t$ with Poi-counting series:
 if $\epsilon_t \equiv 1$, then Poi-INGARCH of Ferland et al. (2006).
- We propose **semi-parametric INGARCH model**:
 ϵ_t with finite support, parameters $p_{\epsilon,2}, p_{\epsilon,3}, \dots$ chosen subject to constraint $\sum_{l \geq 2} l \cdot p_{\epsilon,l} < 1$,
 where $p_{\epsilon,0} = \sum_{l \geq 2} (l-1) \cdot p_{\epsilon,l}$ and $p_{\epsilon,1} = 1 - p_{\epsilon,0} - \sum_{l \geq 2} p_{\epsilon,l}$.

Special case: **binomial-multiplic. CMEM** $X_t = M_t \otimes \epsilon_t$,
satisfying $E[X_t | \mathcal{F}_{t-1}] = M_t$ and

$$V[X_t | \mathcal{F}_{t-1}] = (M_t - \lfloor M_t \rfloor)(1 - M_t + \lfloor M_t \rfloor) + \sigma^2 M_t^2.$$

In Weiß & Zhu (2023), we prove:

- inequality for variance:

$$\mu^2\sigma^2 + (\sigma^2 + 1)V[M_t] \leq V[X_t] \leq 0.25 + \mu^2\sigma^2 + (\sigma^2 + 1)V[M_t],$$

where $V[M_t] = \sum_{i=1}^p a_i \gamma_X(i) + \sum_{j=1}^q b_j \gamma_M(j)$;

- if $\sum_{i=1}^p a_i + \sum_{j=1}^q b_j < 1$,

then weakly dependent stationary and ergodic solution.



HELMUT SCHMIDT
UNIVERSITÄT
Universität der Bundeswehr Hamburg

MATH
STAT

Parameter Estimation and Model Diagnostics

Approaches & Simulations

In Weïß & Zhu (2023), we derive several **semi-parametric estimation** approaches:

- quasi-maximum likelihood estimation (QMLE), namely Poi-QMLE, NB-QMLE, and exponential QMLE,
- two-stage weighted least squares estimation (2SWLSE).

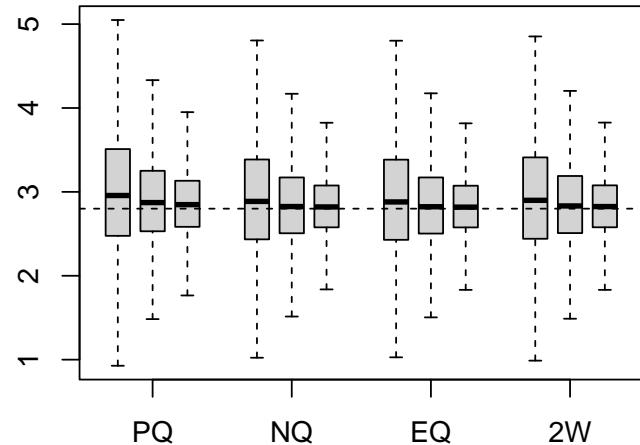
QMLE relies only on conditional mean M_t , estimation of σ^2 by utilizing conditional variance.

2SWLSE uses both conditional mean and variance.

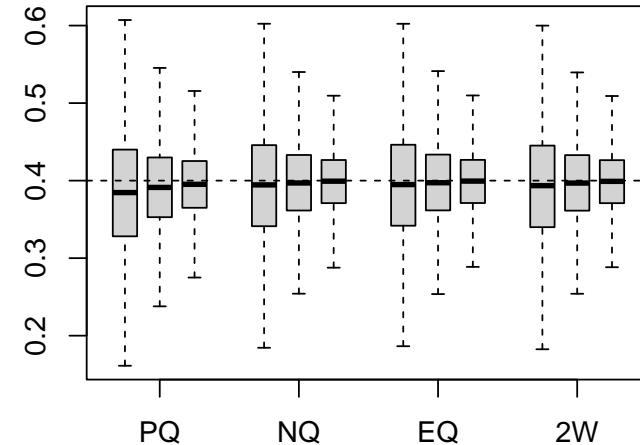
We use residual-based **model diagnostics**.

Simulations for finite-sample performance (also misspecific.).

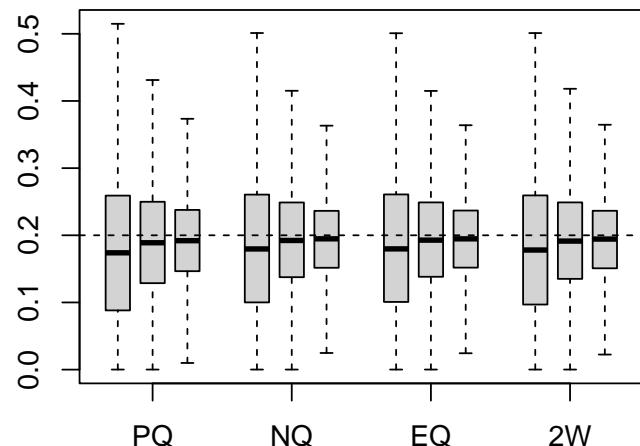
Estimation of $a_0 = 2.8$



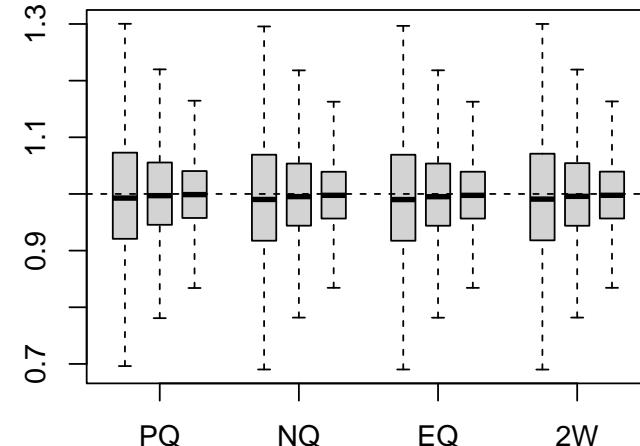
Estimation of $a_1 = 0.4$



Estimation of $b_1 = 0.2$



Estimation of $\sigma^2 = 1$





HELMUT SCHMIDT
UNIVERSITÄT
Universität der Bundeswehr Hamburg

MATH
STAT

Real-World Data Examples

Illustration

For illustration, we discuss **two data examples** from literature:

- Escherichia coli (Ecoli) disease counts
from Aknouche & Scotto (2023),
- Wausau Paper Corporation (WPP) transaction counts
from Aknouche et al. (2022).

Fit INGARCH(1, 1)-CMEM with Poi- and Bin-counting series.

Both in-sample performance and predictive performance
superior to competing models.

PQ-fitted CMEMs show best predictive performance.

Detailed discussion in Weiß & Zhu (2023).

- Novel framework for transferring well-established MEMs for real-valued time series to case of count time series.
- Proposed CMEMs use multiplicative operator for counts.
- Existence of stationary and ergodic solutions, moment properties, semi-parametric model estimation.

Future research:

- CMEMs using other multiplicative operator (e.g., ZIP), or non-linear model specifications (logit, softplus, . . .).
 - Semi-parametric ML estimation for INGARCH models, like semi-parametric INAR approach of Drost et al. (2009).
-

Thank You for Your Interest!



HELMUT SCHMIDT
UNIVERSITÄT

Universität der Bundeswehr Hamburg

MATH
STAT

Christian H. Weiß

Department of Mathematics & Statistics
Helmut Schmidt University, Hamburg
weissc@hsu-hh.de

Weïß & Zhu (2023) Conditional-mean multiplicative operator models for count time series. *CSDA*, under review (arXiv:2212.05831).

- Aknouche & Scotto (2023) A multiplicative thinning-based . . . *JTSA*, forthc.
- Aknouche et al. (2022) Forecasting trans. . . *St Nonl D Econ* **26**, 529–539.
- Brownlees et al. (2012) Mult. error models. *Handb Vola. . .*, Wiley, 223–247.
- Cipollini & Gallo (2023) Multiplicative error models. *Econ Stat*, forthc.
- Drost et al. (2009) Efficient estimation of . . . *JRSS-B* **71**, 467–485.
- Doukhan & Neumann (2019) Absolute regularity of . . . *JAP* **56**, 91–115.
- Engle (2002) New frontiers for ARCH models. *J Appl Econ* **17**, 425–446.
- Engle & Russell (1998) Autoregr. cond. . . *Econometrica* **66**, 1127–1162.
- Ferland et al. (2006) Integer-valued GARCH processes. *JTSA* **27**, 923–942.
- Heinen (2003) Modelling time series count . . . *CORE Disc Paper* 2003/62.
- Latour (1998) Existence and stochastic structure . . . *JTSA* **19**, 439–455.
- Weïß (2018) *An Introduction to Discrete-Valued Time Series*. Wiley.